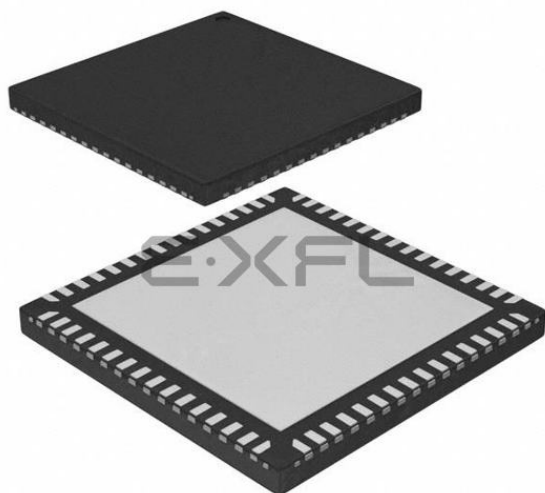




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Details

Product Status	Active
Core Processor	AVR
Core Size	8/16-Bit
Speed	32MHz
Connectivity	I ² C, IrDA, SPI, UART/USART, USB
Peripherals	Brown-out Detect/Reset, DMA, POR, PWM, WDT
Number of I/O	50
Program Memory Size	192KB (96K x 16)
Program Memory Type	FLASH
EEPROM Size	2K x 8
RAM Size	16K x 8
Voltage - Supply (Vcc/Vdd)	1.6V ~ 3.6V
Data Converters	A/D 16x12b; D/A 2x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	64-VFQFN Exposed Pad
Supplier Device Package	64-QFN (9x9)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/atxmega192a3u-mh

7. Memories

7.1 Features

- Flash program memory
 - One linear address space
 - In-system programmable
 - Self-programming and boot loader support
 - Application section for application code
 - Application table section for application code or data storage
 - Boot section for application code or boot loader code
 - Separate read/write protection lock bits for all sections
 - Built in fast CRC check of a selectable flash program memory section
- Data memory
 - One linear address space
 - Single-cycle access from CPU
 - SRAM
 - EEPROM
 - Byte and page accessible
 - Optional memory mapping for direct load and store
 - I/O memory
 - Configuration and status registers for all peripherals and modules
 - 16 bit-accessible general purpose registers for global variables or flags
 - Bus arbitration
 - Deterministic priority handling between CPU, DMA controller, and other bus masters
 - Separate buses for SRAM, EEPROM and I/O memory
 - Simultaneous bus access for CPU and DMA controller
- Production signature row memory for factory programmed data
 - ID for each microcontroller device type
 - Serial number for each device
 - Calibration bytes for factory calibrated peripherals
- User signature row
 - One flash page in size
 - Can be read and written from software
 - Content is kept after chip erase

7.2 Overview

The Atmel AVR architecture has two main memory spaces, the program memory and the data memory. Executable code can reside only in the program memory, while data can be stored in the program memory and the data memory. The data memory includes the internal SRAM, and EEPROM for nonvolatile data storage. All memory spaces are linear and require no memory bank switching. Nonvolatile memory (NVM) spaces can be locked for further write and read/write operations. This prevents unrestricted access to the application software. A separate memory section contains the fuse bytes. These are used for configuring important system functions, and can only be written by an external programmer.

The available memory size configurations are shown in [“Ordering Information” on page 3](#). In addition, each device has a Flash memory signature row for calibration data, device identification, serial number etc.

Table 7-3. Data memory map (Hexadecimal address).

Byte Address	ATxmega192A3U	Byte Address	ATxmega128A3U	Byte Address	ATxmega64A3U
0	I/O Registers (4K)	0	I/O Registers (4K)	0	I/O Registers (4K)
FFF		FFF		FFF	
1000		1000		1000	
17FF	EEPROM (2K)	17FF	EEPROM (2K)	17FF	EEPROM (2K)
	RESERVED		RESERVED		RESERVED
2000	Internal SRAM (16K)	2000	Internal SRAM (8K)	2000	Internal SRAM (4K)
5FFF		3FFF		2FFF	

Byte Address	ATxmega256A3U
0	I/O Registers (4K)
FFF	
1000	
13FF	EEPROM (4K)
	RESERVED
2000	Internal SRAM (16K)
27FF	

7.6 EEPROM

XMEGA AU devices have EEPROM for nonvolatile data storage. It is either addressable in a separate data space (default) or memory mapped and accessed in normal data space. The EEPROM supports both byte and page access. Memory mapped EEPROM allows highly efficient EEPROM reading and EEPROM buffer loading. When doing this, EEPROM is accessible using load and store instructions. Memory mapped EEPROM will always start at hexadecimal address 0x1000.

7.7 I/O Memory

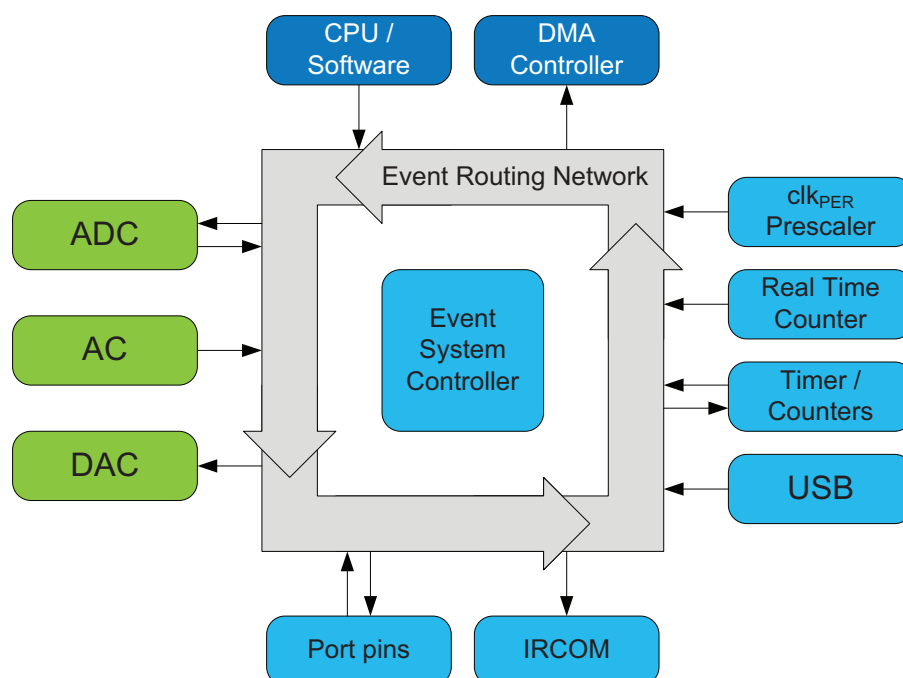
The status and configuration registers for peripherals and modules, including the CPU, are addressable through I/O memory locations. All I/O locations can be accessed by the load (LD/LDS/LDD) and store (ST/STS/STD) instructions, which are used to transfer data between the 32 registers in the register file and the I/O memory. The IN and OUT instructions can address I/O memory locations in the range of 0x00 to 0x3F directly. In the address range 0x00 - 0x1F, single-cycle instructions for manipulation and checking of individual bits are available.

The I/O memory address for all peripherals and modules in XMEGA A3U is shown in the [“Peripheral Module Address Map” on page 64](#).

7.7.1 General Purpose I/O Registers

The lowest 16 I/O memory addresses are reserved as general purpose I/O registers. These registers can be used for storing global variables and flags, as they are directly bit-accessible using the SBI, CBI, SBIS, and SBIC instructions.

Figure 9-1. Event system overview and connected peripherals.



The event routing network consists of eight software-configurable multiplexers that control how events are routed and used. These are called event channels, and allow for up to eight parallel event routing configurations. The maximum routing latency is two peripheral clock cycles. The event system works in both active mode and idle sleep mode.

Base address	Name	Description
0x04A0	TWIE	Two Wire Interface on port E
0x04C0	USB	Universal Serial Bus Interface
0x0600	PORTA	Port A
0x0620	PORTB	Port B
0x0640	PORTC	Port C
0x0660	PORTD	Port D
0x0680	PORTE	Port E
0x06A0	PORTF	Port F
0x07E0	PORTR	Port R
0x0800	TCC0	Timer/Counter 0 on port C
0x0840	TCC1	Timer/Counter 1 on port C
0x0880	AWEXC	Advanced Waveform Extension on port C
0x0890	HIRESC	High Resolution Extension on port C
0x08A0	USARTC0	USART 0 on port C
0x08B0	USARTC1	USART 1 on port C
0x08C0	SPIC	Serial Peripheral Interface on port C
0x08F8	IRCOM	Infrared Communication Module
0x0900	TCD0	Timer/Counter 0 on port D
0x0940	TCD1	Timer/Counter 1 on port D
0x0990	HIRESD	High Resolution Extension on port D
0x09A0	USARTD0	USART 0 on port D
0x09B0	USARTD1	USART 1 on port D
0x09C0	SPID	Serial Peripheral Interface on port D
0x0A00	TCE0	Timer/Counter 0 on port E
0x0A90	HIRESE	High Resolution Extension on port E
0x0AA0	USARTE0	USART 0 on port E
0x0AB0	USARTE1	USART 1 on port E
0x0AC0	SPIE	Serial Peripheral Interface on port E
0x0B00	TCF0	Timer/Counter 0 on port F

36.1.16 Two-Wire Interface Characteristics

Table 36-32 describes the requirements for devices connected to the Two-Wire Interface Bus. The Atmel AVR XMEGA Two-Wire Interface meets or exceeds these requirements under the noted conditions. Timing symbols refer to Figure 36-7.

Figure 36-7. Two-wire interface bus timing.

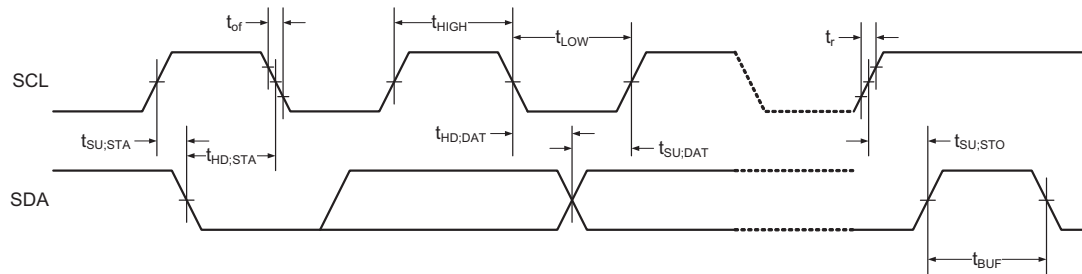


Table 36-32. Two-wire interface characteristics.

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
V_{IH}	Input High Voltage		$0.7 \cdot V_{CC}$		$V_{CC} + 0.5$	V
V_{IL}	Input Low Voltage		-0.5		$0.3 \cdot V_{CC}$	V
V_{hys}	Hysteresis of Schmitt Trigger Inputs		$0.05 \cdot V_{CC}^{(1)}$		0	V
V_{OL}	Output Low Voltage	3mA, sink current	0		0.4	V
t_r	Rise Time for both SDA and SCL		$20 + 0.1 \cdot C_b^{(1)(2)}$		0	ns
t_{of}	Output Fall Time from V_{IHmin} to V_{ILmax}	$10pF < C_b < 400pF^{(2)}$	$20 + 0.1 \cdot C_b^{(1)(2)}$		300	ns
t_{SP}	Spikes Suppressed by Input Filter		0		50	ns
I_I	Input Current for each I/O Pin	$0.1V_{CC} < V_I < 0.9V_{CC}$	-10		10	μA
C_I	Capacitance for each I/O Pin				10	pF
f_{SCL}	SCL Clock Frequency	$f_{PER}^{(3)} > \max(10f_{SCL}, 250kHz)$	0		400	kHz
R_p	Value of Pull-up resistor	$f_{SCL} \leq 100kHz$	$\frac{V_{CC} - 0.4V}{3mA}$		$\frac{100ns}{C_b}$	Ω
		$f_{SCL} > 100kHz$			$\frac{300ns}{C_b}$	
$t_{HD,STA}$	Hold Time (repeated) START condition	$f_{SCL} \leq 100kHz$	4.0			μs
		$f_{SCL} > 100kHz$	0.6			
t_{LOW}	Low Period of SCL Clock	$f_{SCL} \leq 100kHz$	4.7			μs
		$f_{SCL} > 100kHz$	1.3			
t_{HIGH}	High Period of SCL Clock	$f_{SCL} \leq 100kHz$	4.0			μs
		$f_{SCL} > 100kHz$	0.6			

Table 36-46. Accuracy characteristics.

Symbol	Parameter	Condition		Min.	Typ.	Max.	Units
RES	Input Resolution					12	Bits
INL ⁽¹⁾	Integral non-linearity	$V_{REF} = \text{Ext } 1.0V$	$V_{CC} = 1.6V$		± 2.0	± 3	lsb
			$V_{CC} = 3.6V$		± 1.5	± 2.5	
		$V_{REF} = AV_{CC}$	$V_{CC} = 1.6V$		± 2.0	± 4	
			$V_{CC} = 3.6V$		± 1.5	± 4	
		$V_{REF} = \text{INT}1V$	$V_{CC} = 1.6V$		± 5.0		
			$V_{CC} = 3.6V$		± 5.0		
DNL ⁽¹⁾	Differential non-linearity	$V_{REF} = \text{Ext } 1.0V$	$V_{CC} = 1.6V$		± 1.5	3	lsb
			$V_{CC} = 3.6V$		± 0.6	1.5	
		$V_{REF} = AV_{CC}$	$V_{CC} = 1.6V$		± 1.0	3.5	
			$V_{CC} = 3.6V$		± 0.6	1.5	
		$V_{REF} = \text{INT}1V$	$V_{CC} = 1.6V$		± 4.5		
			$V_{CC} = 3.6V$		± 4.5		
	Gain error	After calibration			<4		lsb
	Gain calibration step size				4		lsb
	Gain calibration drift	$V_{REF} = \text{Ext } 1.0V$			<0.2		mV/K
	Offset error	After calibration			<1		lsb
	Offset calibration step size				1		

Note: 1. Maximum numbers are based on characterisation and not tested in production, and valid for 5% to 95% output voltage range.

36.2.8 Analog Comparator Characteristics

Table 36-47. Analog Comparator characteristics.

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
V_{off}	Input Offset Voltage			$<\pm 10$		mV
I_{lk}	Input Leakage Current			<1		nA
	Input voltage range		-0.1		AV_{CC}	V
	AC startup time			100		μs
V_{hys1}	Hysteresis, None			0		mV
V_{hys2}	Hysteresis, Small	mode = High Speed (HS)		13		mV
		mode = Low Power (LP)		30		
V_{hys3}	Hysteresis, Large	mode = HS		30		mV
		mode = LP		60		

Table 36-95. SPI timing characteristics and requirements.

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
t_{SCK}	SCK Period	Master		(See Table 21-4 in XMEGA AU Manual)		ns
t_{SCKW}	SCK high/low width	Master		$0.5 \cdot SCK$		
t_{SCKR}	SCK Rise time	Master		2.7		
t_{SCKF}	SCK Fall time	Master		2.7		
t_{MIS}	MISO setup to SCK	Master		10		
t_{MIH}	MISO hold after SCK	Master		10		
t_{MOS}	MOSI setup SCK	Master		$0.5 \cdot SCK$		
t_{MOH}	MOSI hold after SCK	Master		1		
t_{SSCK}	Slave SCK Period	Slave	$4 \cdot t_{Clk_{PER}}$			
t_{SSCKW}	SCK high/low width	Slave	$2 \cdot t_{Clk_{PER}}$			
t_{SSCKR}	SCK Rise time	Slave			1600	
t_{SSCKF}	SCK Fall time	Slave			1600	
t_{SIS}	MOSI setup to SCK	Slave	3			
t_{SIH}	MOSI hold after SCK	Slave	$t_{Clk_{PER}}$			
t_{SSS}	$\overline{SS}$ setup to SCK	Slave	21			
t_{SSH}	$\overline{SS}$ hold after SCK	Slave	20			
t_{SOS}	MISO setup SCK	Slave		8		
t_{SOH}	MISO hold after SCK	Slave		13		
t_{SOSS}	MISO setup after $\overline{SS}$ low	Slave		11		
t_{SOSH}	MISO hold after $\overline{SS}$ high	Slave		8		

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
$t_{SU;STA}$	Set-up time for a repeated START condition	$f_{SCL} \leq 100\text{kHz}$	4.7			μs
		$f_{SCL} > 100\text{kHz}$	0.6			
$t_{HD;DAT}$	Data hold time	$f_{SCL} \leq 100\text{kHz}$	0		3.45	μs
		$f_{SCL} > 100\text{kHz}$	0		0.9	
$t_{SU;DAT}$	Data setup time	$f_{SCL} \leq 100\text{kHz}$	250			ns
		$f_{SCL} > 100\text{kHz}$	100			
$t_{SU;STO}$	Setup time for STOP condition	$f_{SCL} \leq 100\text{kHz}$	4.0			μs
		$f_{SCL} > 100\text{kHz}$	0.6			
t_{BUF}	Bus free time between a STOP and START condition	$f_{SCL} \leq 100\text{kHz}$	4.7			μs
		$f_{SCL} > 100\text{kHz}$	1.3			

- Notes:
1. Required only for $f_{SCL} > 100\text{kHz}$.
 2. C_b = Capacitance of one bus line in pF.
 3. f_{PER} = Peripheral clock frequency.

Figure 37-25. I/O pin output voltage vs. source current.

$V_{CC} = 3.3V$.

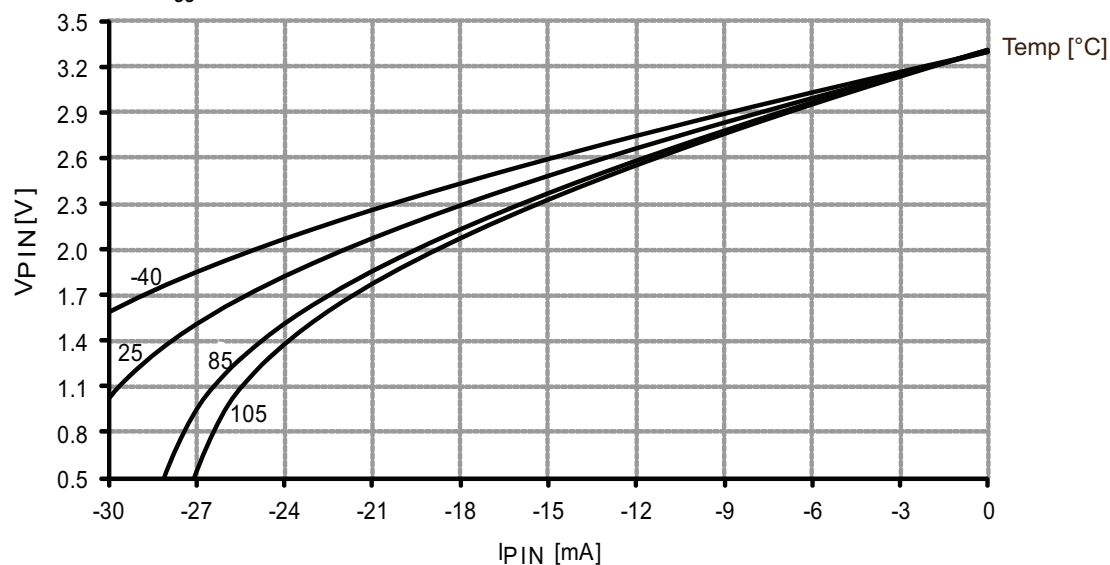


Figure 37-26. I/O pin output voltage vs. source current.

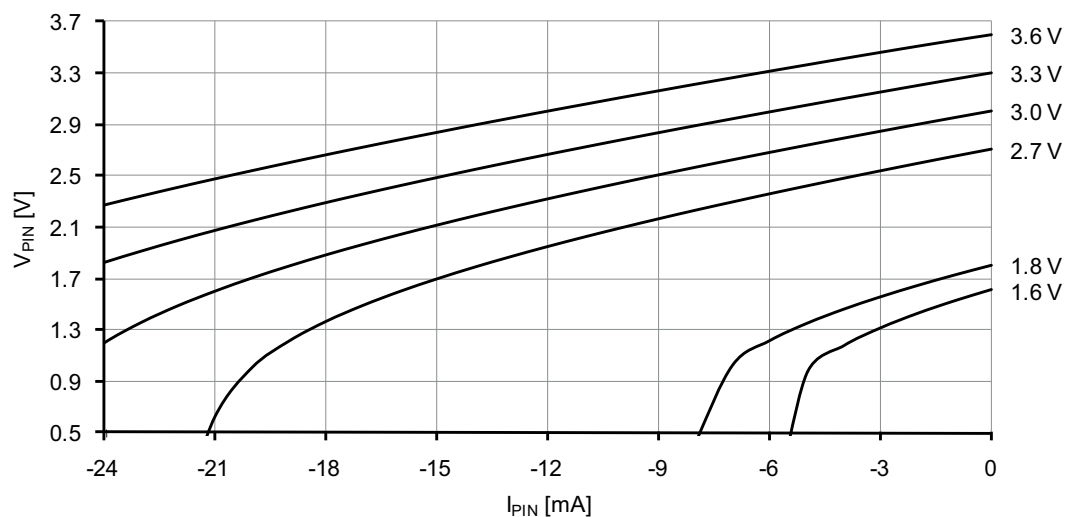


Figure 37-33. I/O pin input threshold voltage vs. V_{CC} .
 V_{IL} I/O pin read as "0".

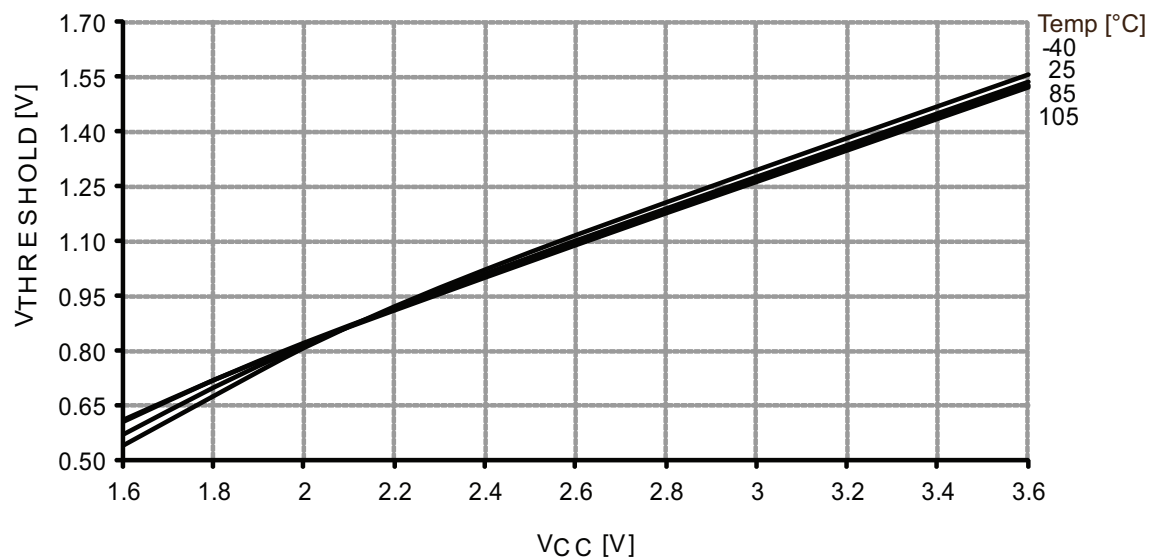


Figure 37-34. I/O pin input hysteresis vs. V_{CC} .

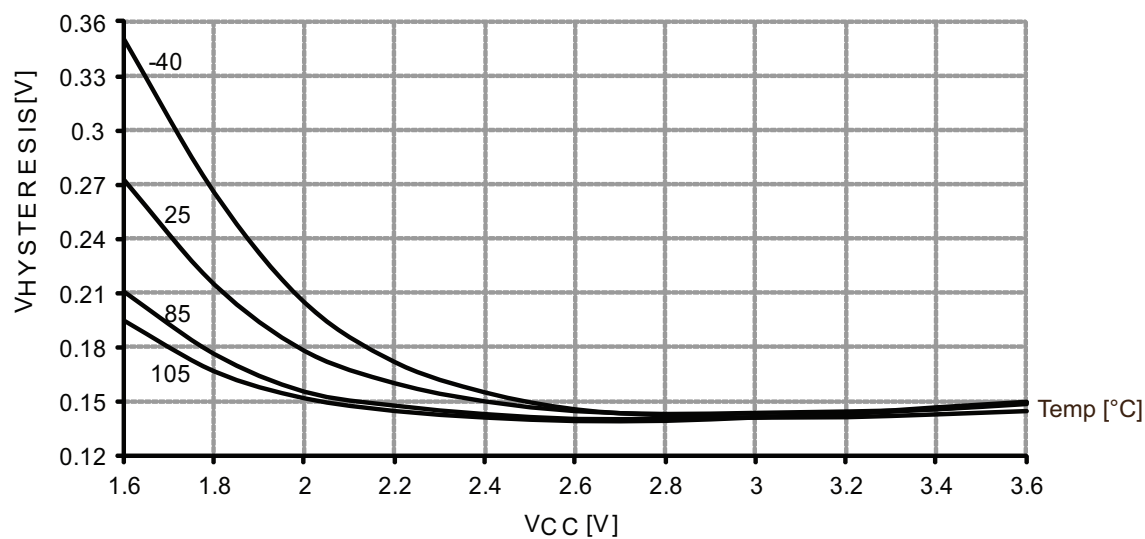


Figure 37-63. Reset pin pull-up resistor current vs. reset pin voltage.

$V_{CC} = 3.0V$.

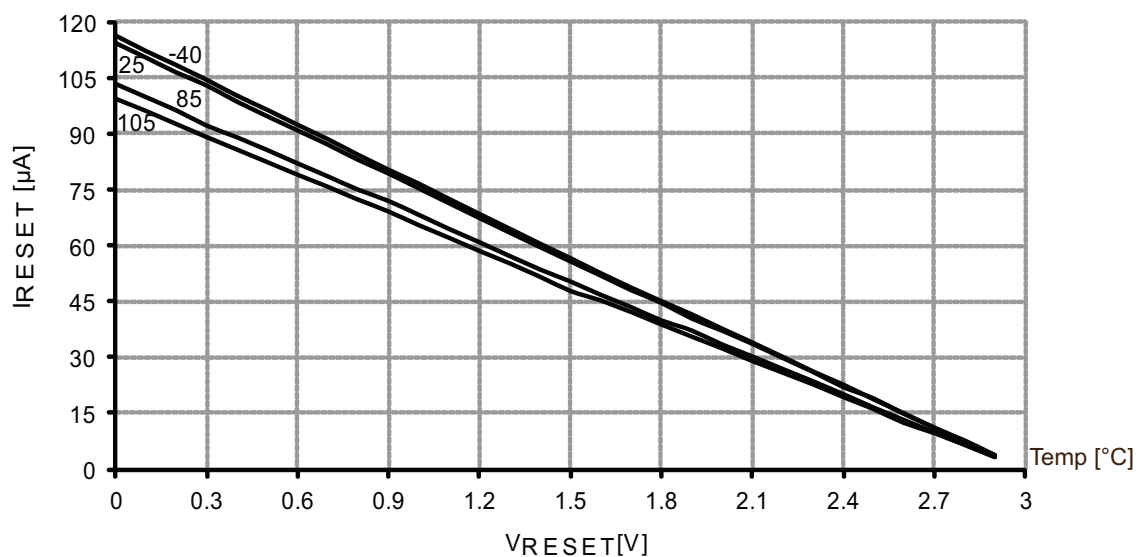


Figure 37-64. Reset pin pull-up resistor current vs. reset pin voltage.

$V_{CC} = 3.3V$.

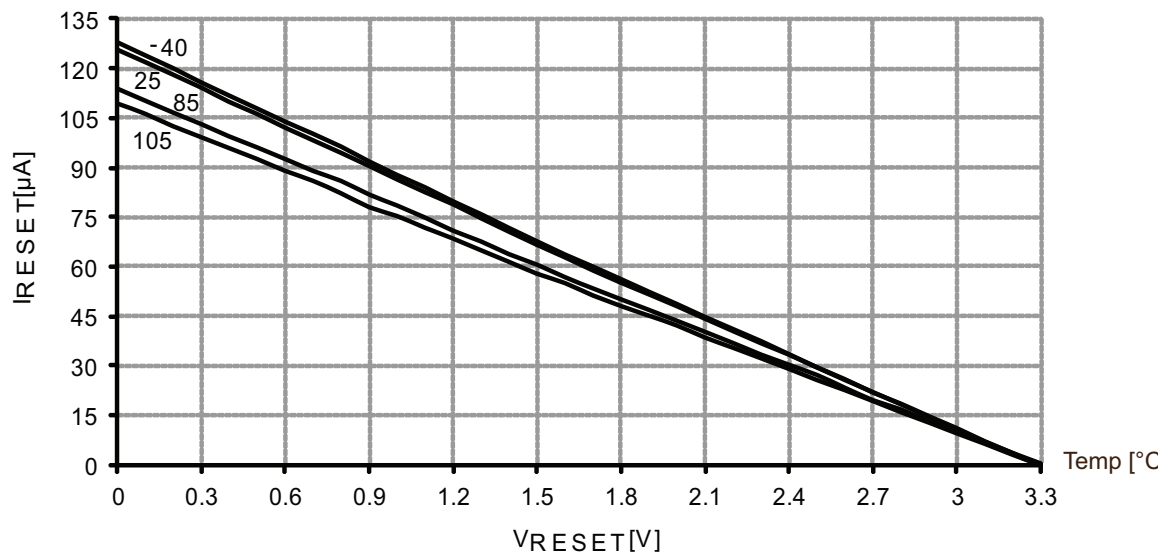


Figure 37-72. 2MHz internal oscillator frequency vs. temperature.
DPLL enabled, from the 32.768kHz internal oscillator.

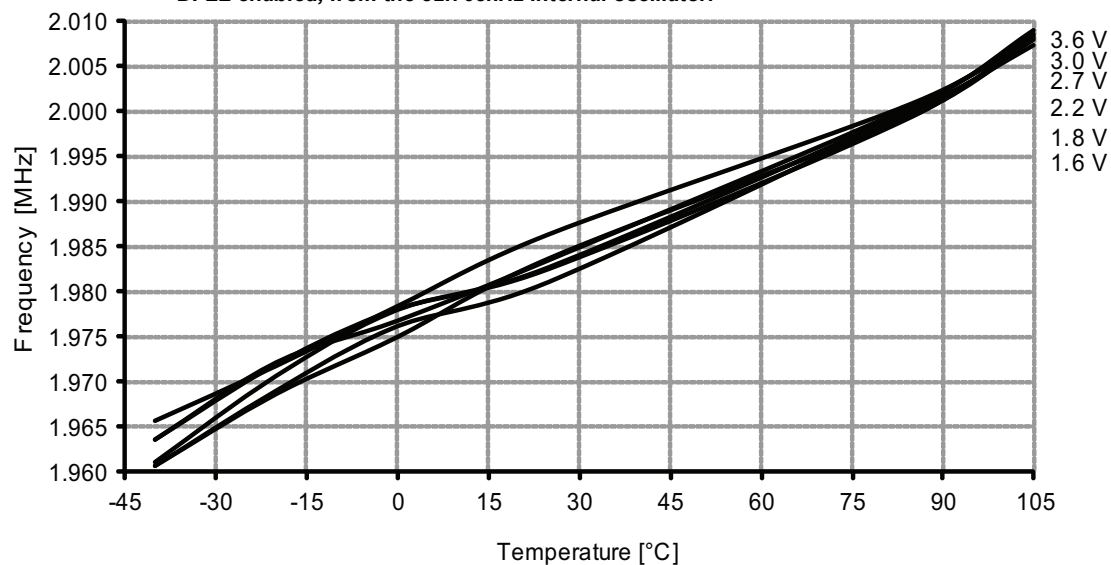
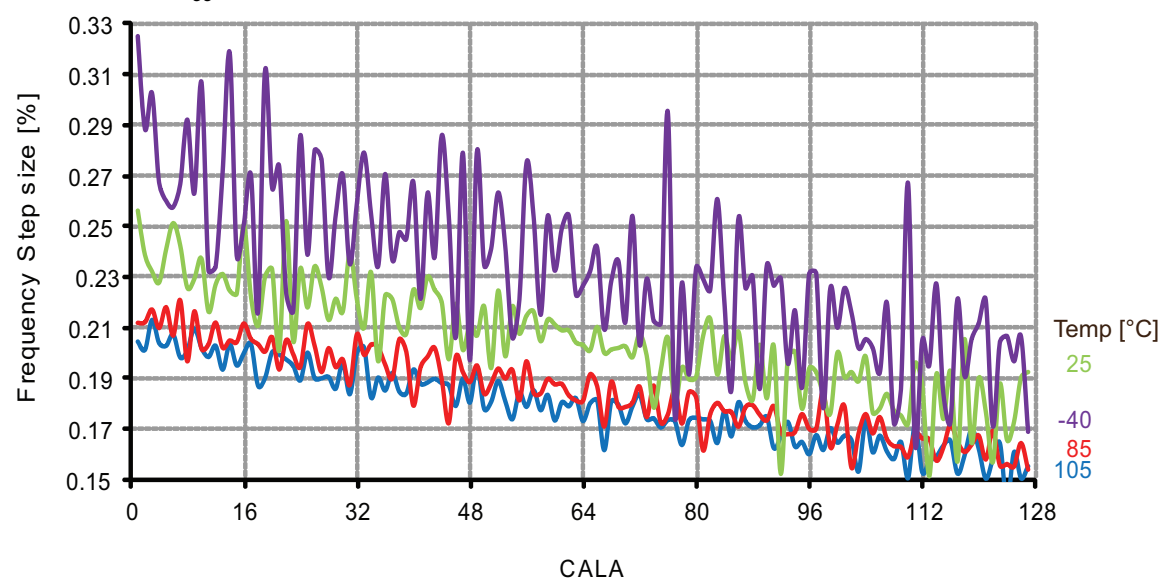


Figure 37-73. 2MHz internal oscillator CALA calibration step size.
 $V_{CC} = 3V$.



37.1.10.4 32MHz Internal Oscillator

Figure 37-74. 32MHz internal oscillator frequency vs. temperature.
DPLL disabled.

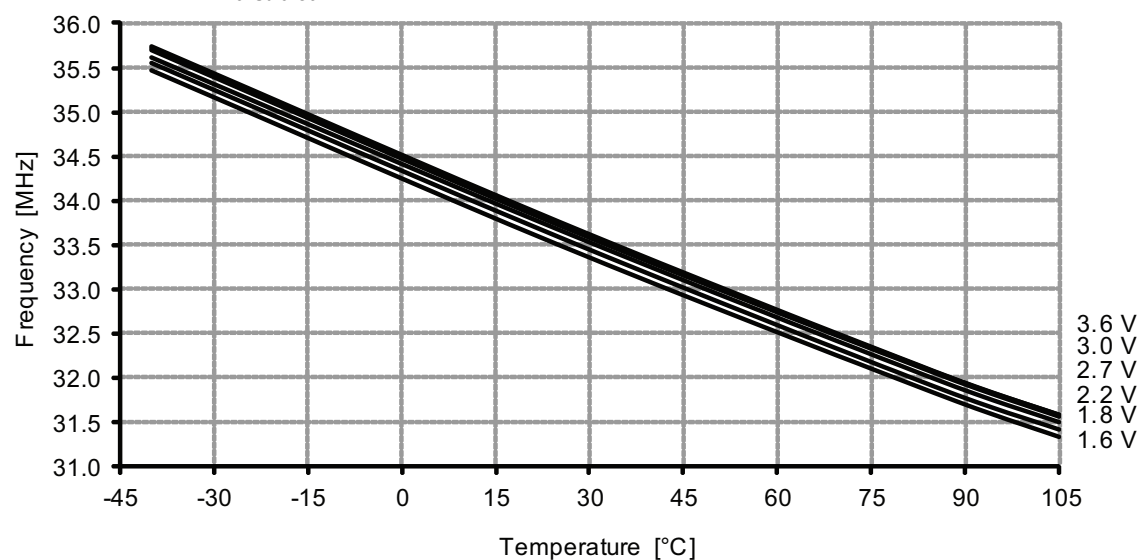
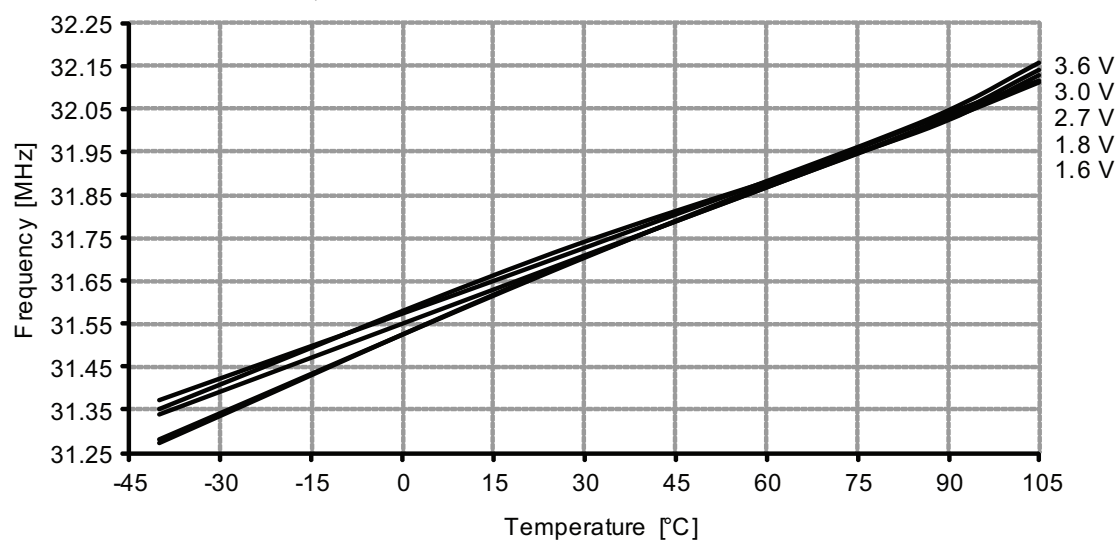


Figure 37-75. 32MHz internal oscillator frequency vs. temperature.
DPLL enabled, from the 32.768kHz internal oscillator.



37.2.2.3 Thresholds and Hysteresis

Figure 37-114. I/O pin input threshold voltage vs. V_{CC} .
 $T = 25^{\circ}\text{C}$.

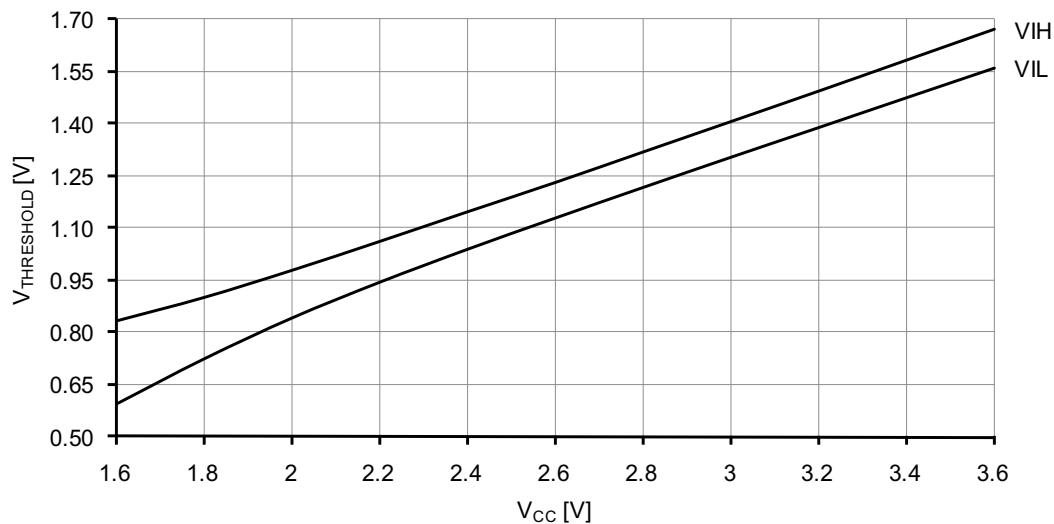


Figure 37-115. I/O pin input threshold voltage vs. V_{CC} .
 V_{IH} I/O pin read as "1".

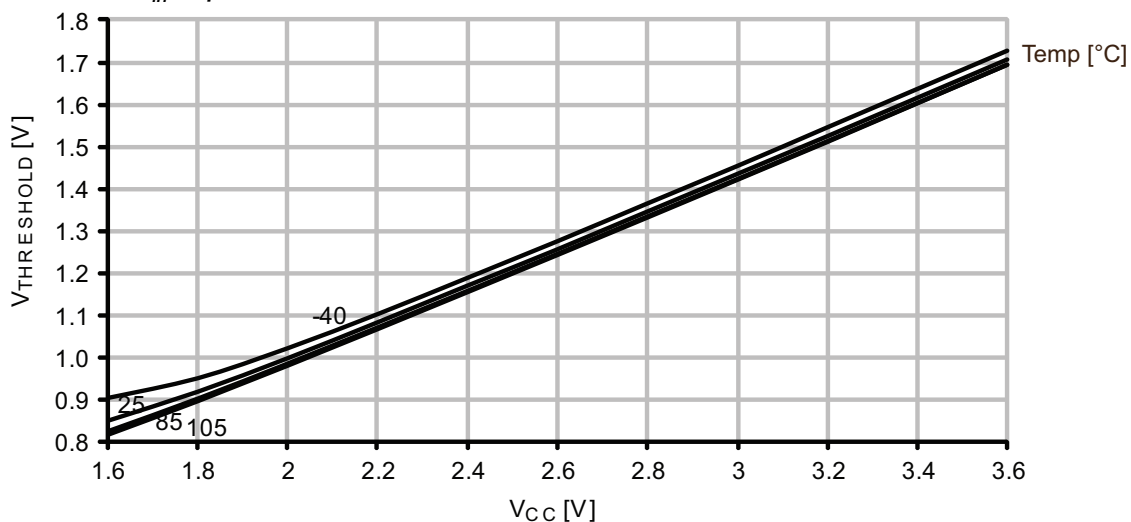


Figure 37-128. Offset error vs. V_{CC} .

$T = 25^{\circ}\text{C}$, $V_{REF} = \text{external } 1.0\text{V}$, ADC sampling speed = 500kps.

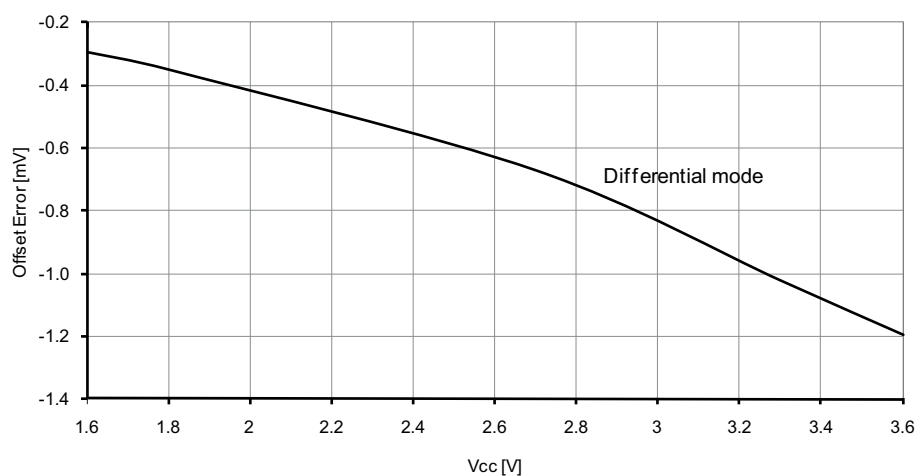


Figure 37-129. Noise vs. V_{REF} .

$T = 25^{\circ}\text{C}$, $V_{CC} = 3.6\text{V}$, ADC sampling speed = 500kps.

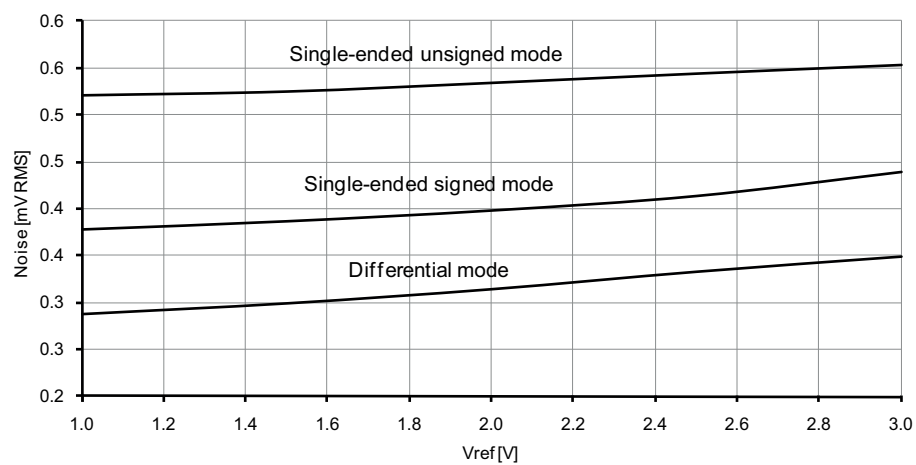


Figure 37-211. Offset error vs. V_{CC} .

$T = 25^{\circ}\text{C}$, $V_{REF} = \text{external } 1.0\text{V}$, ADC sampling speed = 500kps.

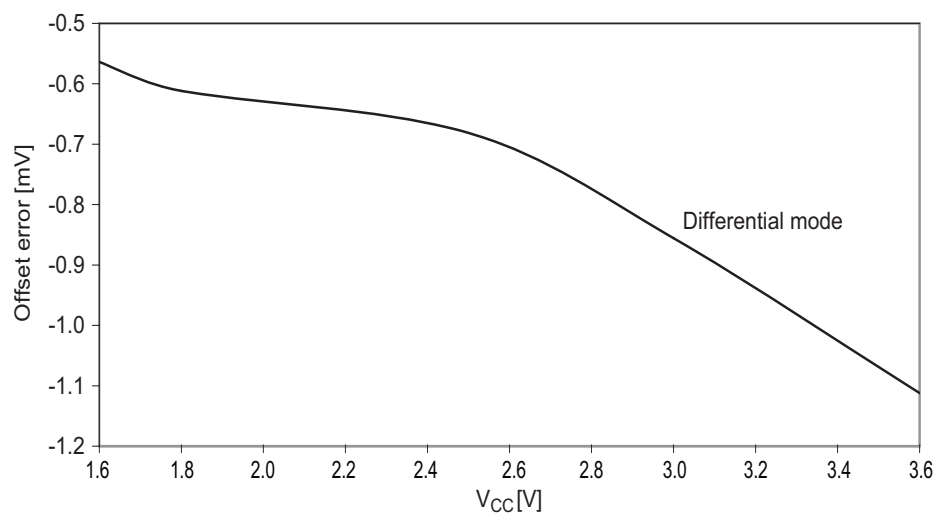
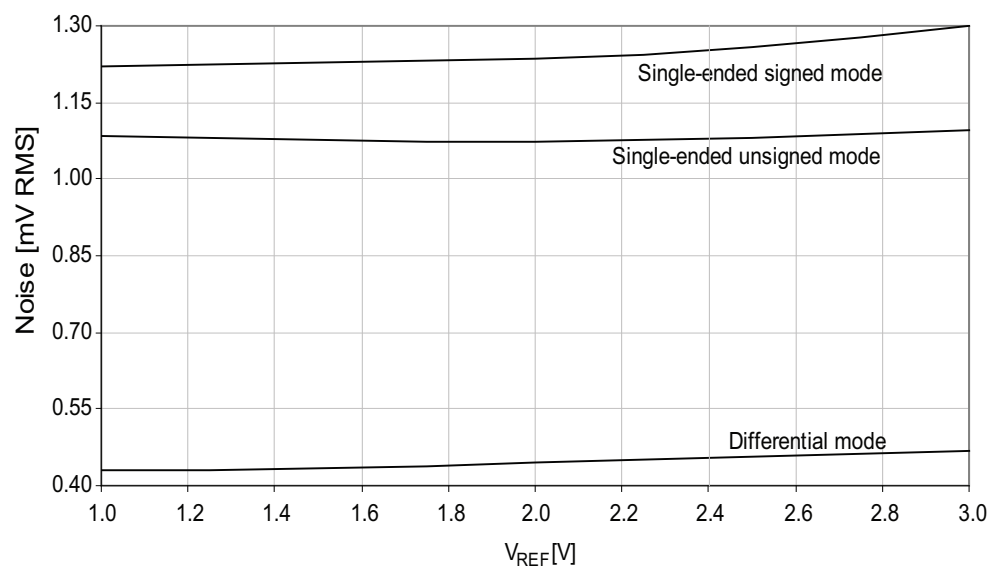


Figure 37-212. Noise vs. V_{REF} .

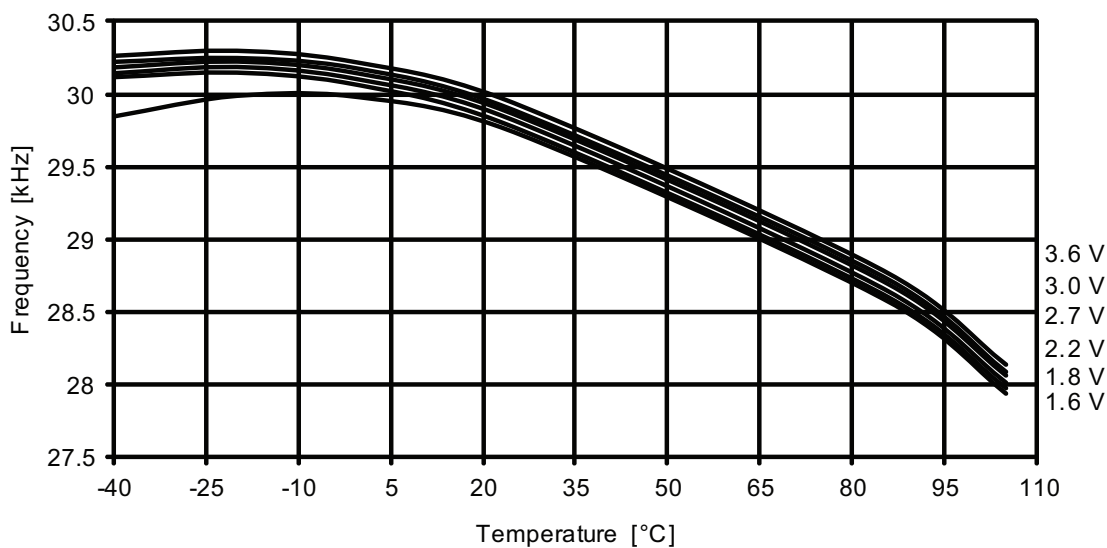
$T = 25^{\circ}\text{C}$, $V_{CC} = 3.6\text{V}$, ADC sampling speed = 500kps.



37.3.10 Oscillator Characteristics

37.3.10.1 Ultra Low-Power internal oscillator

Figure 37-234. Ultra Low-Power internal oscillator frequency vs. temperature.



37.3.10.2 32.768kHz Internal Oscillator

Figure 37-235. 32.768kHz internal oscillator frequency vs. temperature.

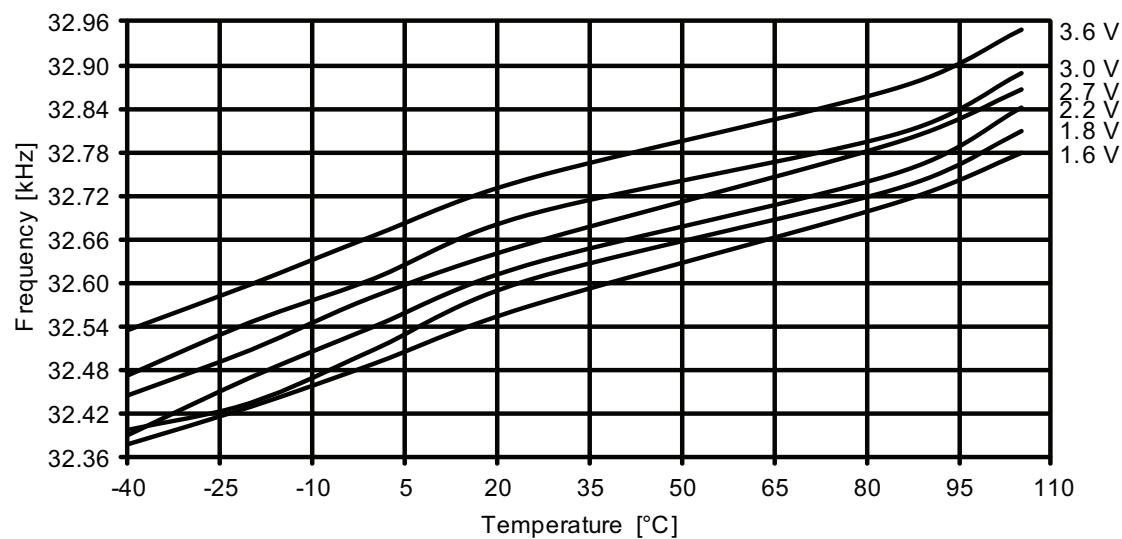
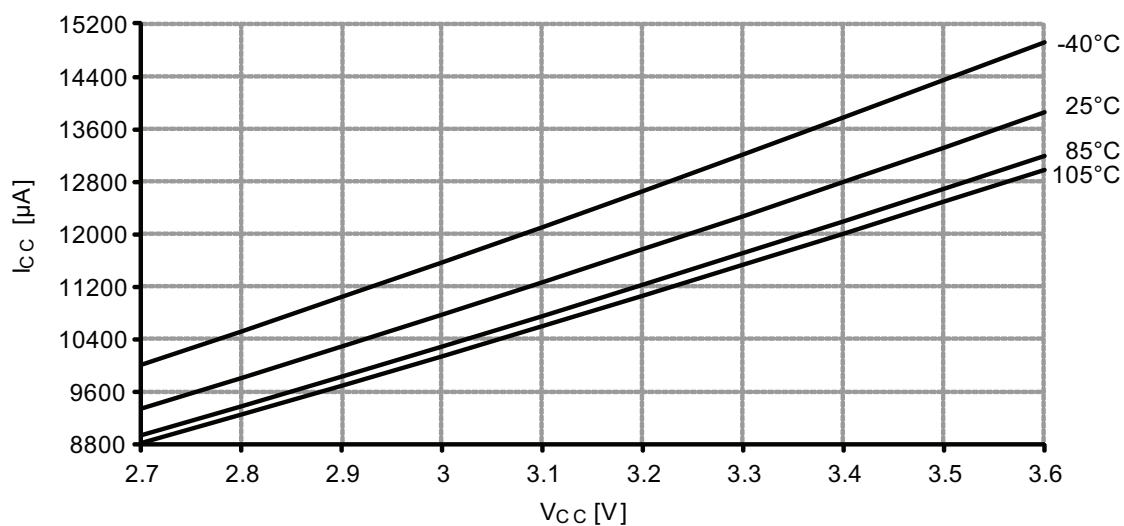


Figure 37-256. Active mode supply current vs. V_{CC} .

$f_{SYS} = 32\text{MHz}$ internal oscillator.



37.4.1.2 Idle mode supply current

Figure 37-257. Idle mode supply current vs. frequency.

$f_{SYS} = 0 - 1\text{MHz}$ external clock, $T = 25^{\circ}\text{C}$.

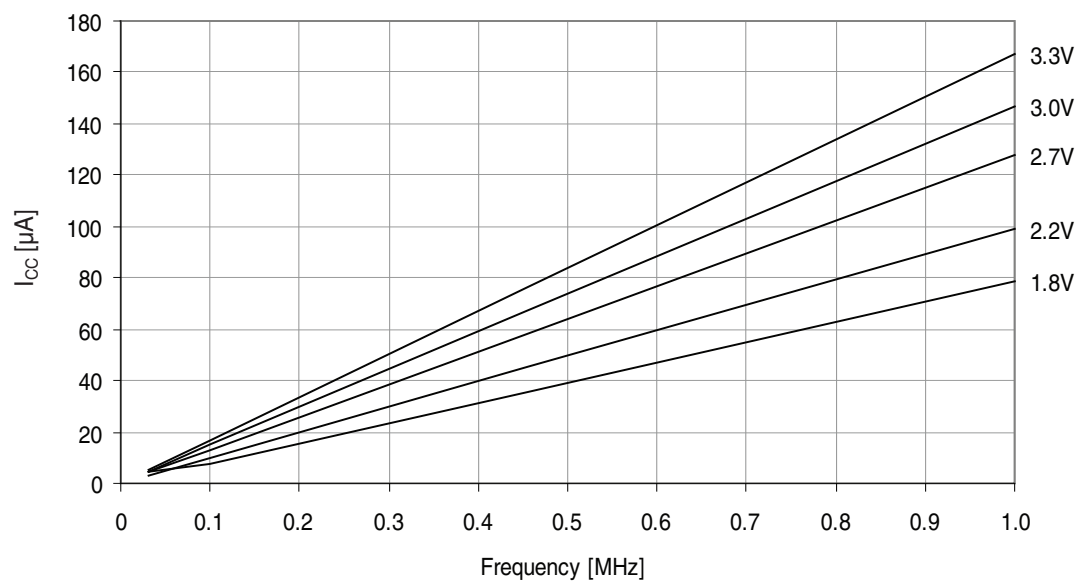


Figure 37-278. I/O pin output voltage vs. sink current.

$V_{CC} = 3.3V$.

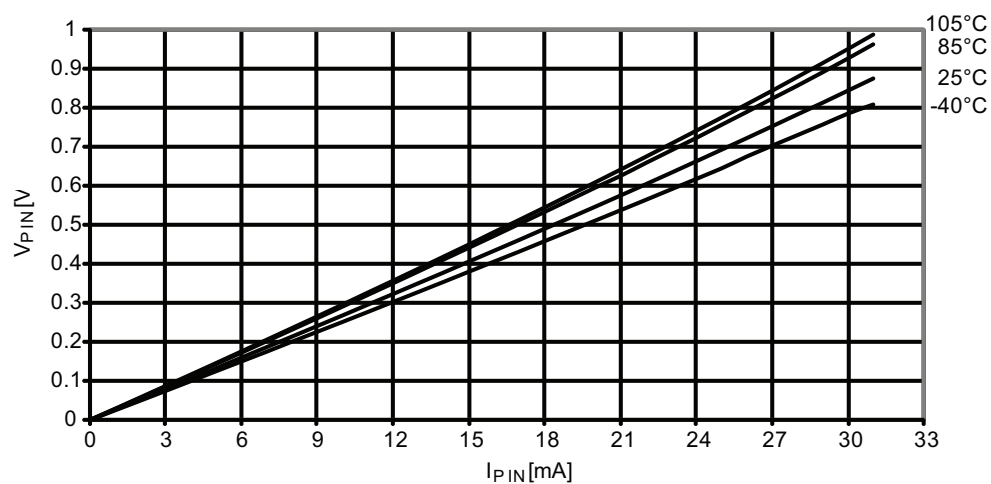


Figure 37-279. I/O pin output voltage vs. sink current.

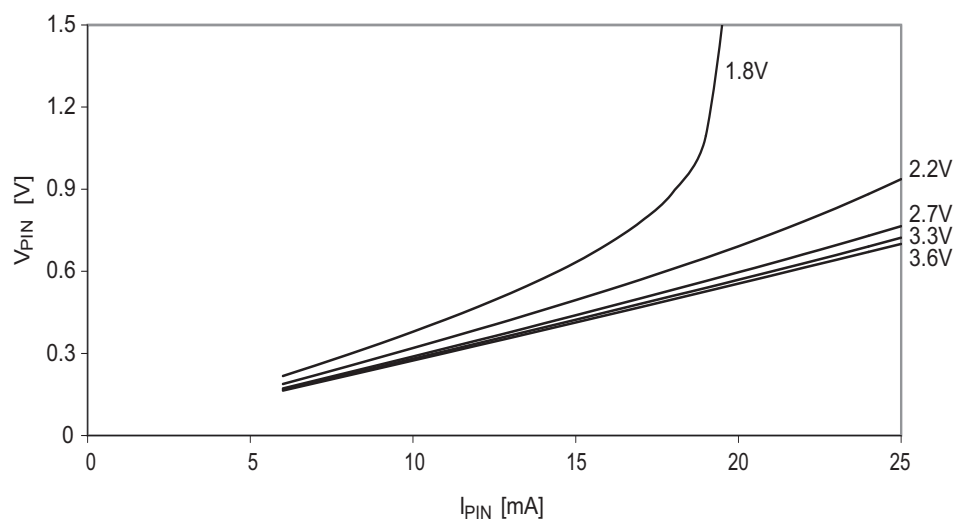
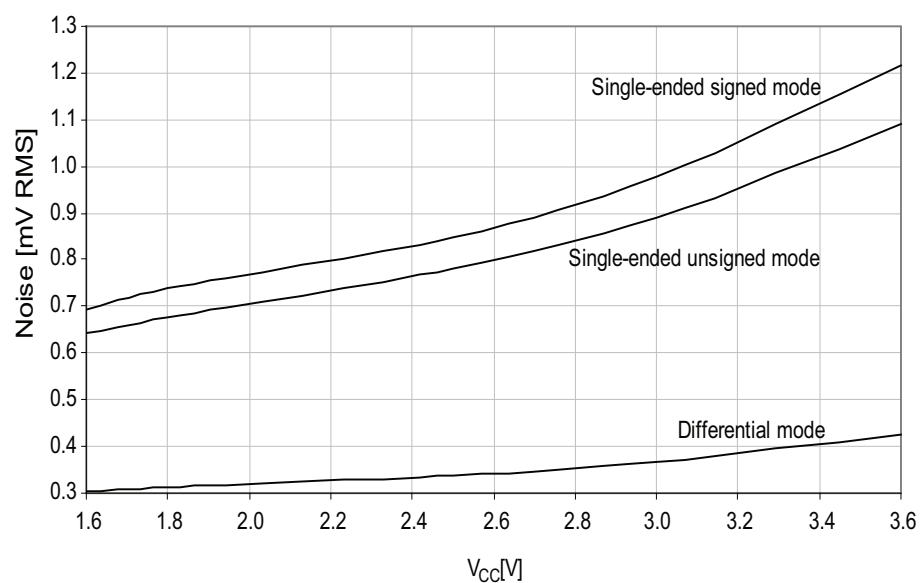


Figure 37-296. Noise vs. V_{CC} .

$T = 25^{\circ}\text{C}$, $V_{REF} = \text{external } 1.0\text{V}$, ADC sampling speed = 500kps.



37.4.4 DAC Characteristics

Figure 37-297. DAC INL error vs. V_{REF} .

$V_{CC} = 3.6\text{V}$.

